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"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Active
Core Processor	Coldfire V1
Core Size	32-Bit Single-Core
Speed	50MHz
Connectivity	EBI/EMI, I ² C, SPI, UART/USART, USB OTG
Peripherals	DMA, I ² S, LVD, POR, PWM, WDT
Number of I/O	35
Program Memory Size	64KB (64K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	16K x 8
Voltage - Supply (Vcc/Vdd)	1.71V ~ 3.6V
Data Converters	A/D 11x12b; D/A 1x12b
Oscillator Type	External
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	48-LQFP
Supplier Device Package	48-LQFP (7x7)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mcf51jf64vlf

3.8 Definition: Typical value

A *typical value* is a specified value for a technical characteristic that:

- Lies within the range of values specified by the operating behavior
- Given the typical manufacturing process, is representative of that characteristic during operation when you meet the typical-value conditions or other specified conditions

Typical values are provided as design guidelines and are neither tested nor guaranteed.

3.8.1 Example 1

This is an example of an operating behavior that includes a typical value:

Symbol	Description	Min.	Typ.	Max.	Unit
I_{WP}	Digital I/O weak pullup/pulldown current	10	70	130	μA

3.8.2 Example 2

This is an example of a chart that shows typical values for various voltage and temperature conditions:

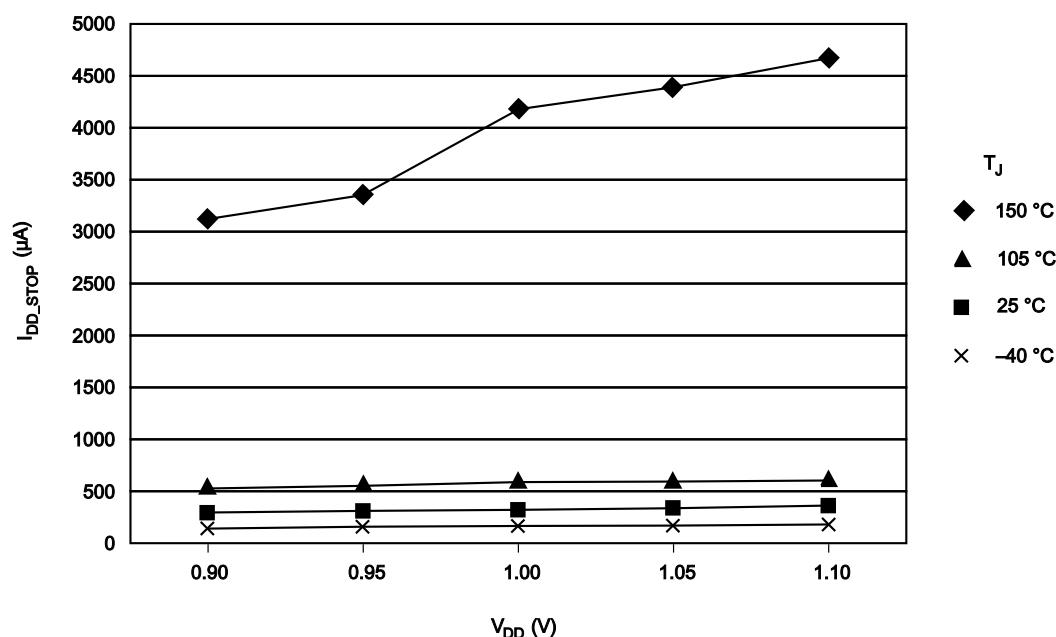


Table 1. Voltage and current operating requirements (continued)

Symbol	Description	Min.	Max.	Unit	Notes
	<ul style="list-style-type: none"> $2.7 \text{ V} \leq V_{DD} \leq 3.6 \text{ V}$ $1.7 \text{ V} \leq V_{DD} \leq 2.7 \text{ V}$ 				
V_{IL}	Input low voltage <ul style="list-style-type: none"> $2.7 \text{ V} \leq V_{DD} \leq 3.6 \text{ V}$ $1.7 \text{ V} \leq V_{DD} \leq 2.7 \text{ V}$ 	—	$0.35 \times V_{DD}$ $0.3 \times V_{DD}$	V V	2
I_{IC}	DC injection current — single pin	0	2	mA	3
	<ul style="list-style-type: none"> $V_{IN} > V_{DD}$ $V_{IN} < V_{SS}$ 	0	-0.2	mA	
	DC injection current — total MCU limit, includes sum of all stressed pins	0	25	mA	3
	<ul style="list-style-type: none"> $V_{IN} > V_{DD}$ $V_{IN} < V_{SS}$ 	0	-5	mA	
V_{RAM}	V_{DD} voltage required to retain RAM	1.2	—	V	

- The device always interprets an input as a 1 when the input is greater than or equal to V_{IH} (min.) and less than or equal to V_{IH} (max.), regardless of whether input hysteresis is turned on.
- The device always interprets an input as a 0 when the input is less than or equal to V_{IL} (max.) and greater than or equal to V_{IL} (min.), regardless of whether input hysteresis is turned on.
- All functional non-supply pins are internally clamped to VSS and VDD. Input must be current limited to the value specified. To determine the value of the required current-limiting resistor, calculate resistance values for positive and negative clamp voltages, then use the larger of the two values. Power supply must maintain regulation within operating VDD range during instantaneous and operating maximum current conditions. If positive injection current ($V_{IN} > V_{DD}$) is greater than IDD, the injection current may flow out of VDD and could result in external power supply going out of regulation. Ensure external VDD load will shunt current greater than maximum injection current. This will be the greatest risk when the MCU is not consuming power. Examples are: if no system clock is present, or if clock rate is very low (which would reduce overall power consumption).

5.2.2 LVD and POR operating requirements

Table 2. LVD and POR operating requirements

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
V_{POR}	Falling VDD POR detect voltage	0.8	1.1	1.5	V	
V_{LVDH}	Falling low-voltage detect threshold — high range (LVDV=01)	2.48	2.56	2.64	V	
V_{LVW1H}	Low-voltage warning thresholds — high range	2.62	2.70	2.78	V	1
V_{LVW2H}	<ul style="list-style-type: none"> Level 1 falling (LVWV=00) 	2.72	2.80	2.88	V	
V_{LVW3H}	<ul style="list-style-type: none"> Level 2 falling (LVWV=01) 	2.82	2.90	2.98	V	
V_{LVW4H}	<ul style="list-style-type: none"> Level 3 falling (LVWV=10) Level 4 falling (LVWV=11) 	2.92	3.00	3.08	V	
V_{HYSH}	Low-voltage inhibit reset/recover hysteresis — high range	—	±80	—	mV	

Table continues on the next page...

Table 3. Voltage and current operating behaviors (continued)

Symbol	Description	Min.	Max.	Unit	Notes
I_{OZ}	Hi-Z (off-state) leakage current (per pin)	—	1	μA	
I_{OZ}	Total Hi-Z (off-state) leakage current (all input pins)	—	4	μA	
R_{PU}	Internal pullup resistors	22	50	$k\Omega$	2
R_{PD}	Internal pulldown resistors	22	50	$k\Omega$	3

1. Tested by ganged leakage method

2. Measured at $V_{input} = V_{SS}$

3. Measured at $V_{input} = V_{DD}$

5.2.4 Power mode transition operating behaviors

All specifications except t_{POR} and VLLSx-RUN recovery times in the following table assume this clock configuration:

- CPU and system clocks = 50 MHz
- Bus clock (and flash and Mini-FlexBus clocks) = 25 MHz

Table 4. Power mode transition operating behaviors

Symbol	Description	Min.	Max.	Unit	Notes
t_{POR}	After a POR event, amount of time from the point V_{DD} reaches 1.71 V to execution of the first instruction across the operating temperature range of the chip.	—	300 1.71 V/(V_{DD} slew rate)	μs	1
	• 1.71 V/(V_{DD} slew rate) \leq 300 μs				
	• 1.71 V/(V_{DD} slew rate) > 300 μs				
	• VLLS1 \rightarrow RUN	—	132	μs	1, 2
	• VLLS2 \rightarrow RUN	—	92	μs	1, 2
	• VLLS3 \rightarrow RUN	—	92	μs	1, 2
	• LLS \rightarrow RUN	—	7.5	μs	2
	• VLPS \rightarrow RUN	—	5.5	μs	2
	• STOP \rightarrow RUN	—	5.5	μs	2

1. Normal boot (FTFL_FOPT[LPBOOT] is 1)

2. The wakeup time includes the execution time for a small amount of firmware used to produce a GPIO clear event. Wakeup time is measured from the falling edge of the external wakeup event to the falling edge of a GPIO clear performed by software.

5.2.5 Power consumption operating behaviors

Table 5. Power consumption operating behaviors

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
I _{DDA}	Analog supply current	—	—	See note	mA	1
I _{DD_RUN}	Run mode current — all peripheral clocks disabled, code executing from RAM <ul style="list-style-type: none"> • @ 1.8 V • @ 3.0 V 	—	13	—	mA	2
I _{DD_RUN}	Run mode current — all peripheral clocks disabled, code executing from flash memory with page buffering disabled <ul style="list-style-type: none"> • @ 1.8 V • @ 3.0 V 	—	14.3 14.5	— 17.9	mA mA	2
I _{DD_RUN}	Run mode current — all peripheral clocks enabled, code executing from RAM, exercising flash memory <ul style="list-style-type: none"> • @ 1.8 V • @ 3.0 V 	—	20 20	23.5 25	mA mA	3
I _{DD_WAIT}	Wait mode current at 3.0 V — all peripheral clocks disabled	—	5.8	6.8	mA	4
I _{DD_STOP}	Stop mode current at 3.0 V <ul style="list-style-type: none"> • @ -40 to 25 °C • @ 105 °C 	—	0.34 0.90	0.41 1.8	mA mA	
I _{DD_VLPR}	Very low-power run mode current at 3.0 V — all peripheral clocks disabled	—	0.63	1.32	mA	5
I _{DD_VLPR}	Very low-power run mode current at 3.0 V — all peripheral clocks enabled	—	0.78	1.46	mA	6
I _{DD_VLPW}	Very low-power wait mode current at 3.0 V	—	0.15	0.62	mA	7
I _{DD_VLPS}	Very low-power stop mode current at 3.0 V <ul style="list-style-type: none"> • @ -40 to 25 °C • @ 105 °C 	—	19 145	45 312	µA	8
I _{DD_LLS}	Low leakage stop mode current at 3.0 V <ul style="list-style-type: none"> • @ -40 to 25 °C • @ 105 °C 	— —	3.0 53.3	4.8 157	µA µA	8,9,10
I _{DD_VLLS3}	Very low-leakage stop mode 3 current at 3.0 V <ul style="list-style-type: none"> • @ -40 to 25 °C • @ 105 °C 	— —	1.8 39.2	3.3 115	µA µA	8,9,10
I _{DD_VLLS2}	Very low-leakage stop mode 2 current at 3.0 V	— —	1.6 22.2	2.8 65	µA µA	8,9

Table continues on the next page...

Table 5. Power consumption operating behaviors (continued)

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
	<ul style="list-style-type: none"> • @ -40 to 25 °C • @ 105 °C 					
I _{DD_VLLS1}	Very low-leakage stop mode 1 current at 3.0 V <ul style="list-style-type: none"> • @ -40 to 25 °C • @ 105 °C 	—	1.4 17.6	2.6 50	µA	8,9
I _{DD_RTC}	Average current adder for real-time clock function <ul style="list-style-type: none"> • @ -40 to 25 °C 	—	0.7	—	µA	11

1. The analog supply current is the sum of the active current for each of the analog modules on the device. See each module's specification for its supply current.
2. 50 MHz core and system clocks, and 25 MHz bus clock. MCG configured for FEI mode. All peripheral clocks disabled.
3. 50 MHz core and system clocks, and 25 MHz bus clock. MCG configured for FEI mode. All peripheral clocks enabled, but peripherals are not in active operation.
4. 50 MHz core and system clocks, and 25 MHz bus clock. MCG configured for FEI mode.
5. 2 MHz core and system clocks, and 1 MHz bus clock. MCG configured for BLPE mode. All peripheral clocks disabled. Code executing from flash memory.
6. 2 MHz core and system clocks, and 1 MHz bus clock. MCG configured for BLPE mode. All peripheral clocks enabled, but peripherals are not in active operation. Code executing from flash memory.
7. 2 MHz core and system clocks, and 1 MHz bus clock. MCG configured for BLPE mode. All peripheral clocks disabled.
8. OSC clocks disabled.
9. All pads disabled.
10. Data reflects devices with 32 KB of RAM. For devices with 16 KB of RAM, power consumption is reduced by 500 nA. For devices with 8 KB of RAM, power consumption is reduced by 750 nA.
11. RTC function current includes LPTMR with OSC enabled with 32.768 kHz crystal at 3.0 V

5.2.5.1 Diagram: Typical IDD_RUN operating behavior

The following data was measured under these conditions:

- MCG in FBE mode, except for 50 MHz core (FEI mode)
- For the ALLOFF curve, all peripheral clocks are disabled except FTFL
- For the ALLON curve, all peripheral clocks are enabled, but peripherals are not in active operation
- USB Voltage Regulator disabled
- No GPIOs toggled
- Code execution from flash memory with cache enabled

6 Peripheral operating requirements and behaviors

6.1 Core modules

6.1.1 Debug specifications

Table 12. Background debug mode (BDM) timing

Number	Symbol	Description	Min.	Max.	Unit
1	t_{MSSU}	BKGD/MS setup time after issuing background debug force reset to enter user mode or BDM	500	—	ns
2	t_{MSH}	BKGD/MS hold time after issuing background debug force reset to enter user mode or BDM ¹	100	—	μs

1. To enter BDM mode following a POR, BKGD/MS should be held low during the power-up and for a hold time of t_{MSH} after V_{DD} rises above V_{LVD} .

6.2 System modules

There are no specifications necessary for the device's system modules.

6.3 Clock modules

6.3.1 MCG specifications

Table 13. MCG specifications

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
f_{ints_ft}	Internal reference frequency (slow clock) — factory trimmed at nominal VDD and 25 °C	—	32.768	—	kHz	
f_{ints_t}	Internal reference frequency (slow clock) — user trimmed	31.25	—	38.214	kHz	
$\Delta f_{dco_res_t}$	Resolution of trimmed average DCO output frequency at fixed voltage and temperature — using SCTRIM and SCFTRIM	—	± 0.3	± 0.6	% f_{dco}	¹
$\Delta f_{dco_res_t}$	Resolution of trimmed average DCO output frequency at fixed voltage and temperature — using SCTRIM only	—	± 0.2	± 0.5	% f_{dco}	¹
Δf_{dco_t}	Total deviation of trimmed average DCO output frequency over voltage and temperature	—	± 10	—	% f_{dco}	¹

Table continues on the next page...

Table 13. MCG specifications (continued)

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
Δf_{dco_t}	Total deviation of trimmed average DCO output frequency over fixed voltage and temperature range of 0–70°C	—	± 4.5	—	%f _{dco}	1
f _{intf_ft}	Internal reference frequency (fast clock) — factory trimmed at nominal VDD and 25°C	—	3.3	4	MHz	
f _{intf_t}	Internal reference frequency (fast clock) — user trimmed at nominal VDD and 25 °C	3	—	5	MHz	
f _{loc_low}	Loss of external clock minimum frequency — RANGE = 00	(3/5) × f _{ints_t}	—	—	kHz	
f _{loc_high}	Loss of external clock minimum frequency — RANGE = 01, 10, or 11	(16/5) × f _{ints_t}	—	—	kHz	
FLL						
f _{fill_ref}	FLL reference frequency range	31.25	—	39.0625	kHz	
f _{dco}	DCO output frequency range	Low range (DRS=00) 640 × f _{fill_ref}	20	20.97	25	MHz
		Mid range (DRS=01) 1280 × f _{fill_ref}	40	41.94	50	MHz
		Mid-high range (DRS=10) 1920 × f _{fill_ref}	60	62.91	75	MHz
		High range (DRS=11) 2560 × f _{fill_ref}	80	83.89	100	MHz
f _{dco_t_DMX32}	DCO output frequency	Low range (DRS=00) 732 × f _{fill_ref}	—	23.99	—	MHz
		Mid range (DRS=01) 1464 × f _{fill_ref}	—	47.97	—	MHz
		Mid-high range (DRS=10) 2197 × f _{fill_ref}	—	71.99	—	MHz
		High range (DRS=11) 2929 × f _{fill_ref}	—	95.98	—	MHz
J _{cyc_fill}	FLL period jitter • f _{DCO} = 48 MHz • f _{DCO} = 98 MHz	—	180	—	ps	
		—	150	—	ps	
t _{fill_acquire}	FLL target frequency acquisition time	—	—	1	ms	6
PLL						
f _{vco}	VCO operating frequency	48.0	—	100	MHz	
I _{pll}	PLL operating current • PLL @ 96 MHz (f _{osc_hi_1} = 8 MHz, f _{pll_ref} = 2 MHz, VDIV multiplier = 48)	—	1060	—	µA	7
I _{pll}	PLL operating current • PLL @ 48 MHz (f _{osc_hi_1} = 8 MHz, f _{pll_ref} = 2 MHz, VDIV multiplier = 24)	—	600	—	µA	7
f _{pll_ref}	PLL reference frequency range	2.0	—	4.0	MHz	

Table continues on the next page...

Table 14. Oscillator DC electrical specifications (continued)

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
	Peak-to-peak amplitude of oscillation (oscillator mode) — low-frequency, high-gain mode (HGO=1)	—	V _{DD}	—	V	
	Peak-to-peak amplitude of oscillation (oscillator mode) — high-frequency, low-power mode (HGO=0)	—	0.6	—	V	
	Peak-to-peak amplitude of oscillation (oscillator mode) — high-frequency, high-gain mode (HGO=1)	—	V _{DD}	—	V	

1. V_{DD}=3.3 V, Temperature =25 °C
2. See crystal or resonator manufacturer's recommendation
3. C_x and C_y can be provided by using either integrated capacitors or external components.
4. When low-power mode is selected, R_F is integrated and must not be attached externally.
5. The EXTAL and XTAL pins should only be connected to required oscillator components and must not be connected to any other device.

6.3.2.2 Oscillator frequency specifications

Table 15. Oscillator frequency specifications

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
f _{osc_lo}	Oscillator crystal or resonator frequency — low-frequency mode (MCG_C2[RANGE]=00)	32	—	40	kHz	
f _{osc_hi_1}	Oscillator crystal or resonator frequency — high-frequency mode (low range) (MCG_C2[RANGE]=01)	1	—	8	MHz	
f _{osc_hi_2}	Oscillator crystal or resonator frequency — high frequency mode (high range) (MCG_C2[RANGE]=1x)	8	—	32	MHz	
f _{ec_extal}	Input clock frequency (external clock mode)	—	—	50	MHz	1, 2
t _{dc_extal}	Input clock duty cycle (external clock mode)	40	50	60	%	
t _{cst}	Crystal startup time — 32 kHz low-frequency, low-power mode (HGO=0)	—	750	—	ms	3, 4
	Crystal startup time — 32 kHz low-frequency, high-gain mode (HGO=1)	—	250	—	ms	
	Crystal startup time — 8 MHz high-frequency (MCG_C2[RANGE]=01), low-power mode (HGO=0)	—	0.6	—	ms	
	Crystal startup time — 8 MHz high-frequency (MCG_C2[RANGE]=01), high-gain mode (HGO=1)	—	1	—	ms	

1. Other frequency limits may apply when external clock is being used as a reference for the FLL or PLL.
2. When transitioning from FEI or FBI to FBE mode, restrict the frequency of the input clock so that, when it is divided by FRDIV, it remains within the limits of the DCO input clock frequency.
3. Proper PC board layout procedures must be followed to achieve specifications.
4. Crystal startup time is defined as the time between the oscillator being enabled and the OSCINIT bit in the MCG_S register being set.

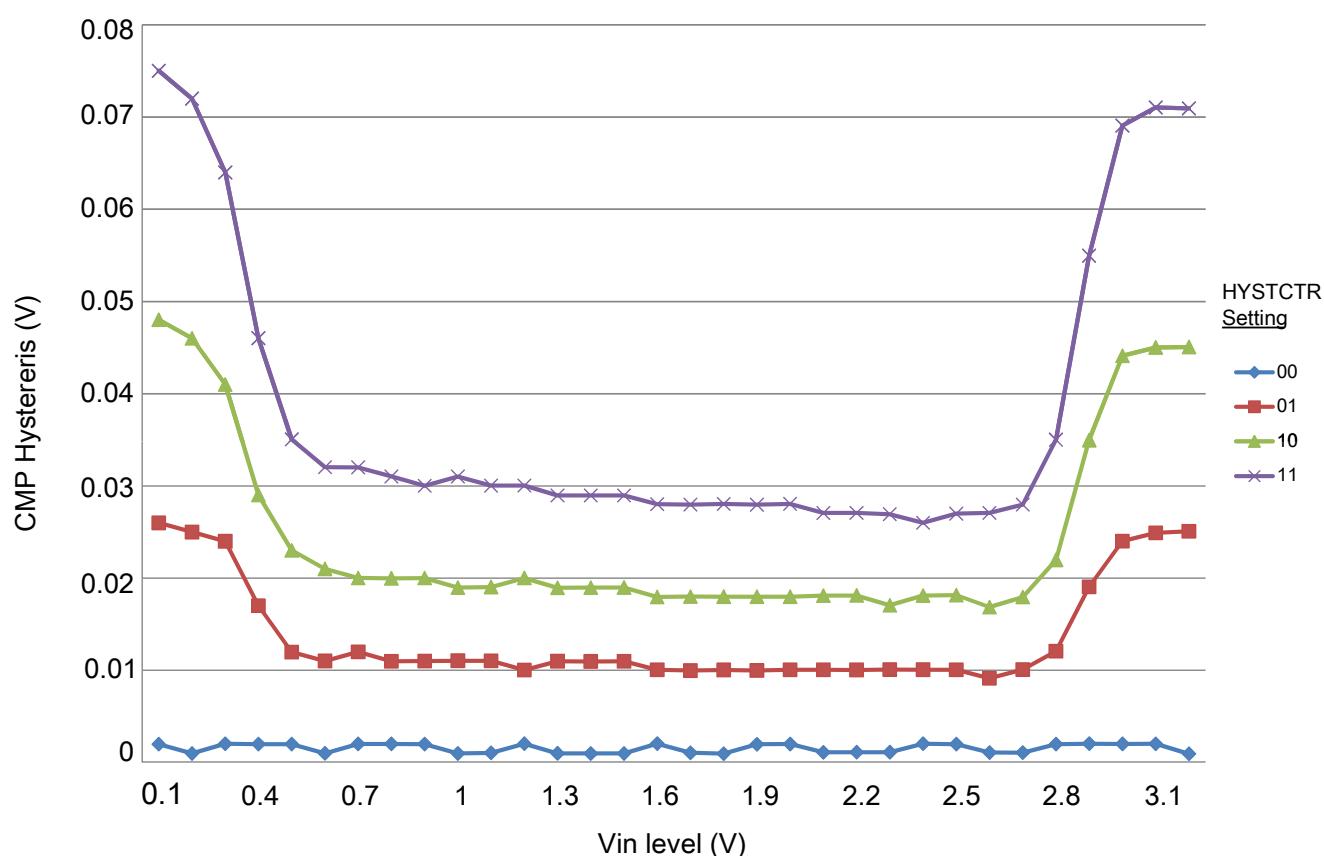


Figure 10. Typical hysteresis vs. Vin level (VDD = 3.3 V, PMODE = 0)

6.6.3.2 12-bit DAC operating behaviors

Table 26. 12-bit DAC operating behaviors

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
I _{DDA_DACL_P}	Supply current — low-power mode	—	—	450	µA	
I _{DDA_DACH_P}	Supply current — high-speed mode	—	—	1000	µA	
t _{DACLP}	Full-scale settling time (0x080 to 0xF7F) — low-power mode	—	100	200	µs	1
t _{DACHP}	Full-scale settling time (0x080 to 0xF7F) — high-power mode	—	15	30	µs	1
t _{CCDACL_P}	Code-to-code settling time (0xBF8 to 0xC08) — low-power mode and high-speed mode	—	0.7	1	µs	1
V _{dacoutl}	DAC output voltage range low — high-speed mode, no load, DAC set to 0x000	—	—	100	mV	
V _{dacouth}	DAC output voltage range high — high-speed mode, no load, DAC set to 0xFFFF	V _{DACR} -100	—	V _{DACR}	mV	
INL	Integral non-linearity error — high speed mode	—	—	±8	LSB	2
DNL	Differential non-linearity error — V _{DACR} > 2 V	—	—	±1	LSB	3
DNL	Differential non-linearity error — V _{DACR} = V _{REF_OUT}	—	—	±1	LSB	4
V _{OFFSET}	Offset error	—	±0.4	±0.8	%FSR	5
E _G	Gain error	—	±0.1	±0.6	%FSR	5
PSRR	Power supply rejection ratio, V _{DDA} ≥ 2.4 V	60	—	90	dB	
T _{CO}	Temperature coefficient offset voltage	—	3.7	—	µV/C	6
T _{GE}	Temperature coefficient gain error	—	0.000421	—	%FSR/C	
R _{op}	Output resistance (load = 3 kΩ)	—	—	250	Ω	
SR	Slew rate -80h→F7Fh→80h • High power (SP _{HP}) • Low power (SP _{LP})	1.2 0.05	1.7 0.12	—	V/µs	
CT	Channel to channel cross talk	—	—	-80	dB	
BW	3dB bandwidth • High power (SP _{HP}) • Low power (SP _{LP})	550 40	— —	— —	kHz	

- Settling within ±1 LSB
- The INL is measured for 0 + 100 mV to V_{DACR} -100 mV
- The DNL is measured for 0 + 100 mV to V_{DACR} -100 mV
- The DNL is measured for 0 + 100 mV to V_{DACR} -100 mV with V_{DDA} > 2.4 V
- Calculated by a best fit curve from V_{SS} + 100 mV to V_{DACR} -100 mV
- V_{DDA} = 3.0 V, reference select set for V_{DDA} (DACx_CO:DACRFS = 1), high power mode (DACx_C0:LPEN = 0), DAC set to 0x800, temperature range is across the full range of the device

6.8.4 SPI switching specifications

The Serial Peripheral Interface (SPI) provides a synchronous serial bus with master and slave operations. Many of the transfer attributes are programmable. The following tables provide timing characteristics for classic SPI timing modes. See the SPI chapter of the chip's Reference Manual for information about the modified transfer formats used for communicating with slower peripheral devices.

All timing is shown with respect to 20% V_{DD} and 70% V_{DD} , unless noted, as well as input signal transitions of 3 ns and a 50 pF maximum load on all SPI pins. All timing assumes slew rate control is disabled and high drive strength is enabled for SPI output pins.

Table 33. SPI master mode timing

Num.	Symbol	Description	Min.	Max.	Unit	Comment
1	f_{op}	Frequency of operation	$f_{BUS}/2048$	$f_{BUS}/2$	Hz	f_{BUS} is the bus clock as defined in Table 8 .
2	t_{SPSCK}	SPSCK period	$2 \times t_{BUS}$	$2048 \times t_{BUS}$	ns	$t_{BUS} = 1/f_{BUS}$
3	t_{Lead}	Enable lead time	1/2	—	t_{SPSCK}	—
4	t_{Lag}	Enable lag time	1/2	—	t_{SPSCK}	—
5	t_{wSPSCK}	Clock (SPSCK) high or low time	$t_{BUS} - 30$	$1024 \times t_{BUS}$	ns	—
6	t_{SU}	Data setup time (inputs)	21	—	ns	—
7	t_{HI}	Data hold time (inputs)	0	—	ns	—
8	t_v	Data valid (after SPSCK edge)	—	25	ns	—
9	t_{HO}	Data hold time (outputs)	0	—	ns	—
10	t_{RI}	Rise time input	—	$t_{BUS} - 25$	ns	—
	t_{FI}	Fall time input	—			
11	t_{RO}	Rise time output	—	25	ns	—
	t_{FO}	Fall time output	—			

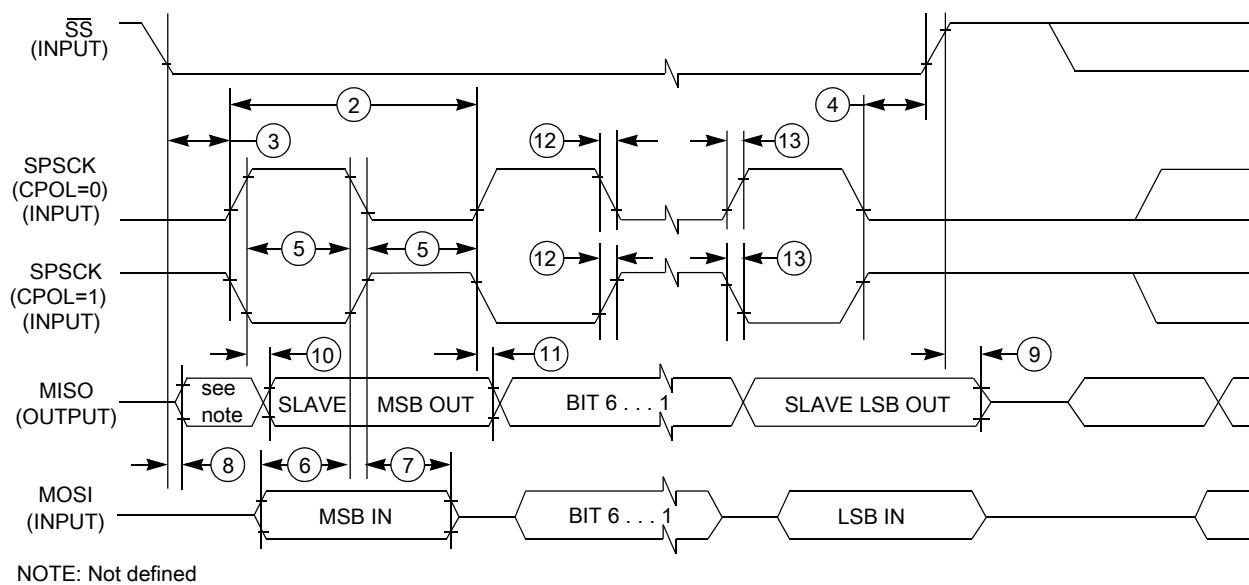


Figure 17. SPI slave mode timing (CPHA=1)

6.8.5 I2S/SAI Switching Specifications

This section provides the AC timing for the I2S/SAI module in master mode (clocks are driven) and slave mode (clocks are input). All timing is given for noninverted serial clock polarity (TCR2[BCP] is 0, RCR2[BCP] is 0) and a noninverted frame sync (TCR4[FSP] is 0, RCR4[FSP] is 0). If the polarity of the clock and/or the frame sync have been inverted, all the timing remains valid by inverting the bit clock signal (BCLK) and/or the frame sync (FS) signal shown in the following figures. All timing shown is also with respect to input signal transitions of 3 ns and a 50 pF maximum load.

Table 35. I2S/SAI master mode timing

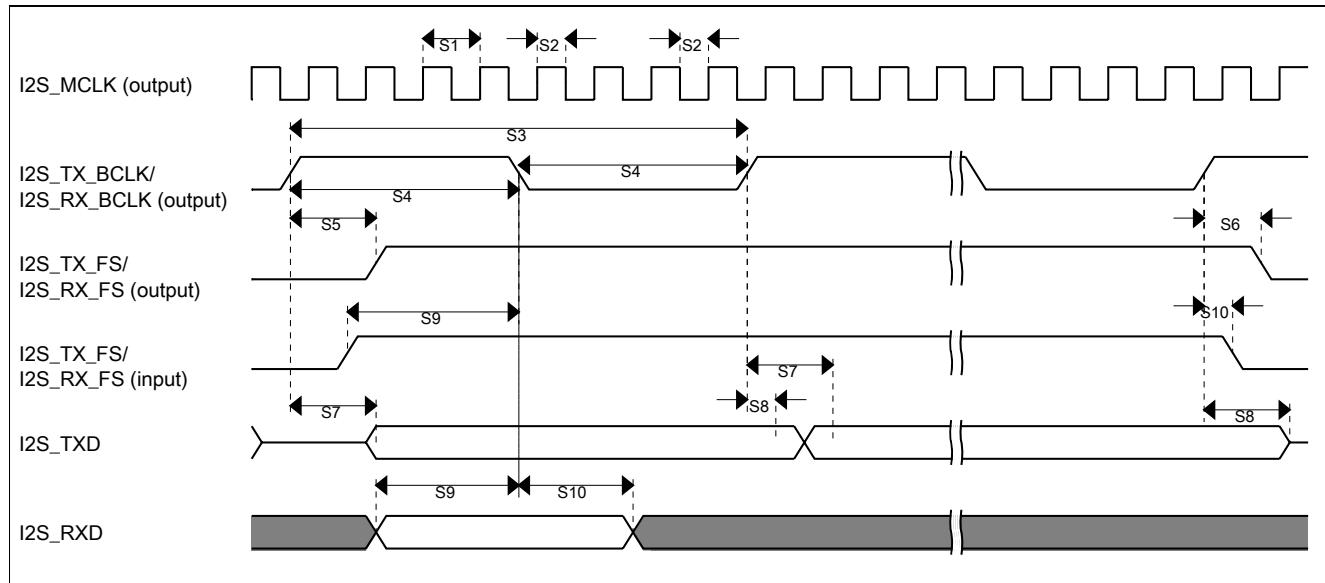
Num.	Characteristic	Min.	Max.	Unit
	Operating voltage	1.71	3.6	V
S1	I2S_MCLK cycle time ¹	40	—	ns
S2	I2S_MCLK (as an input) pulse width high/low	45%	55%	MCLK period
S3	I2S_TX_BCLK/I2S_RX_BCLK cycle time (output)	80	—	ns
S4	I2S_TX_BCLK/I2S_RX_BCLK pulse width high/low	45%	55%	BCLK period
S5	I2S_TX_BCLK/I2S_RX_BCLK to I2S_TX_FS/I2S_RX_FS output valid	—	15	ns
S6	I2S_TX_BCLK/I2S_RX_BCLK to I2S_TX_FS/I2S_RX_FS output invalid	0	—	ns
S7	I2S_TX_BCLK to I2S_TXD valid	—	15	ns
S8	I2S_TX_BCLK to I2S_TXD invalid	0	—	ns
S9	I2S_RXD/I2S_RX_FS input setup before I2S_RX_BCLK	25	—	ns

Table continues on the next page...

Table 35. I2S/SAI master mode timing (continued)

Num.	Characteristic	Min.	Max.	Unit
S10	I2S_RXD/I2S_RX_FS input hold after I2S_RX_BCLK	0	—	ns
S11	I2S_TX_FS input assertion to I2S_TXD output valid ²	—	21	ns

1. This parameter is limited in VLPx modes.
 2. Applies to first bit in each frame and only if the TCR4[FSE] bit is clear

**Figure 18. I2S/SAI timing — master modes****Table 36. I2S/SAI slave mode timing**

Num.	Characteristic	Min.	Max.	Unit
	Operating voltage	1.71	3.6	V
S11	I2S_TX_BCLK/I2S_RX_BCLK cycle time (input)	80	—	ns
	I2S_TX_BCLK cycle time (input)	160	—	
S12	I2S_TX_BCLK/I2S_RX_BCLK pulse width high/low (input)	45%	55%	MCLK period
S13	I2S_TX_FS/I2S_RX_FS input setup before I2S_TX_BCLK/I2S_RX_BCLK	10	—	ns
S14	I2S_TX_FS/I2S_RX_FS input hold after I2S_TX_BCLK/I2S_RX_BCLK	2	—	ns
S15	I2S_TX_BCLK to I2S_TXD/I2S_TX_FS output valid	—	29	ns
S16	I2S_TX_BCLK to I2S_TXD/I2S_TX_FS output invalid	0	—	ns
S17	I2S_RXD setup before I2S_RX_BCLK	10	—	ns
S18	I2S_RXD hold after I2S_RX_BCLK	2	—	ns
S19	I2S_TX_FS input assertion to I2S_TXD output valid ¹	—	21	ns

1. Applies to first bit in each frame and only if the TCR4[FSE] bit is clear

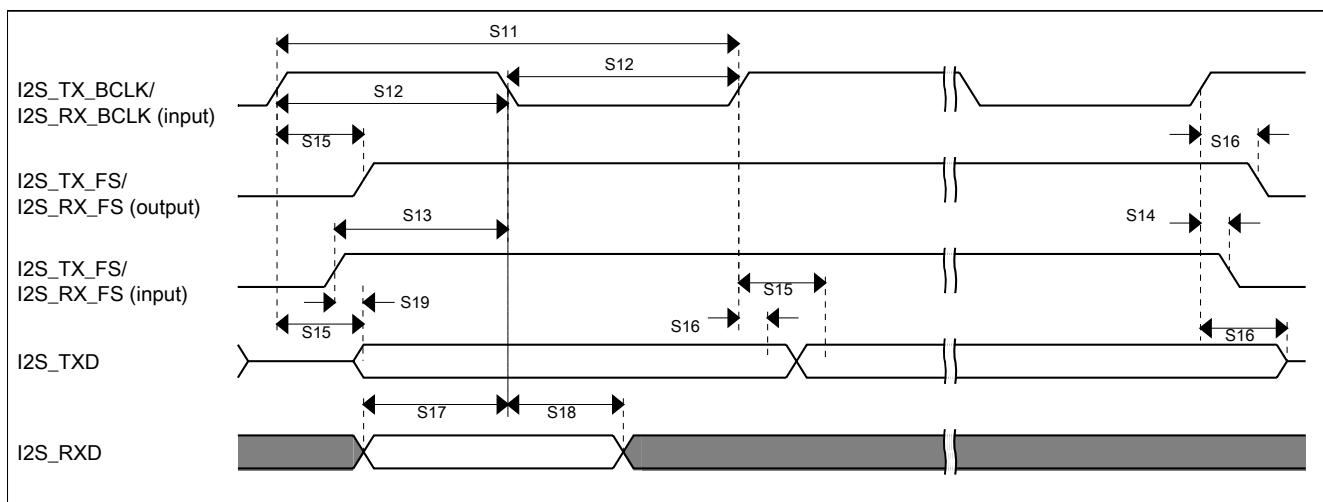


Figure 19. I2S/SAI timing — slave modes

6.9 Human-machine interfaces (HMI)

6.9.1 TSI electrical specifications

Table 37. TSI electrical specifications

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
V_{DDTSI}	Operating voltage	1.71	—	3.6	V	
C_{ELE}	Target electrode capacitance range	1	20	500	pF	1
f_{REFmax}	Reference oscillator frequency	—	5.5	14	MHz	2
f_{ELEmax}	Electrode oscillator frequency	—	0.5	4.0	MHz	3
C_{REF}	Internal reference capacitor	0.5	1	1.2	pF	
V_{DELTA}	Oscillator delta voltage	100	600	760	mV	4
I_{REF}	Reference oscillator current source base current • 1uA setting (REFCHRG=0) • 32uA setting (REFCHRG=31)	—	1.133	1.5	µA	3, 5
I_{ELE}	Electrode oscillator current source base current • 1uA setting (EXTCHRG=0) • 32uA setting (EXTCHRG=31)	—	1.133	1.5	µA	3, 6
Pres5	Electrode capacitance measurement precision	—	8.3333	38400	fF/count	7
Pres20	Electrode capacitance measurement precision	—	8.3333	38400	fF/count	8
Pres100	Electrode capacitance measurement precision	—	8.3333	38400	fF/count	9
MaxSens	Maximum sensitivity	0.003	12.5	—	fF/count	10
Res	Resolution	—	—	16	bits	
T_{Con20}	Response time @ 20 pF	8	15	25	µs	11
I_{TSI_RUN}	Current added in run mode	—	55	—	µA	
I_{TSI_LP}	Low power mode current adder	—	1.3	2.5	µA	12

64-pin	48-pin	44-pin	32-pin	Default	ALT0	ALT1	ALT2	ALT3	ALT4	ALT5	ALT6	ALT7	EzPort
22	18	16	13	USB0_DP	USB0_DP								
23	19	17	14	VSS	VSS								
24	20	18	—	VDD	VDD								
25	21	19	15	ADC0_SE8/ TSI0_CH0	ADC0_SE8/ TSI0_CH0	PTA6		LPTMR_ ALT1	FTM_FLT1	FBa_D7	FBa_AD17		
26	—	—	—	ADC0_SE9/ TSI0_CH1	ADC0_SE9/ TSI0_CH1	PTD2	FTM0_QD_ PHA	GPIO10	FTM0_CH0				
27	22	20	—	ADC0_SE10/ TSI0_CH2	ADC0_SE10/ TSI0_CH2	PTD3	FTM0_QD_ PHB	GPIO11	FTM0_CH1	FBa_D6	FBa_AD0		
28	—	—	—	ADC0_SE11/ TSI0_CH3	ADC0_SE11/ TSI0_CH3	PTD4		GPIO12			FBa_D7		
29	—	—	—	ADC0_SE12/ TSI0_CH4	ADC0_SE12/ TSI0_CH4	PTD5		GPIO13			FBa_D6		
30	23	21	16	ADC0_SE13/ TSI0_CH5	ADC0_SE13/ TSI0_CH5	PTA7	UART0_TX		FTM0_QD_ PHA		FBa_D5		
31	24	22	—	ADC0_SE14/ TSI0_CH6	ADC0_SE14/ TSI0_CH6	PTD6	UART0_RX	GPIO14			FBa_D4		
32	—	—	—	ADC0_SE15/ TSI0_CH7	ADC0_SE15/ TSI0_CH7	PTD7	UART0_ CTS_b	I2C3_SCL	GPIO15		FBa_D3		
33	—	—	—	TSI0_CH8	TSI0_CH8	PTE0	UART0_ RTS_b	I2C3_SDA			FBa_D2		
34	—	—	—	TSI0_CH9	TSI0_CH9	PTE1	SPI0_SS		FTM_FLT0		FBa_D1		
35	25	23	17	IRQ/ EZP_MS_b	Disabled	PTB0		I2C0_SCL		IRQ/ EZP_MS_b			EZP_CS_b
36	26	24	18	TSI0_CH10	TSI0_CH10	PTB1	SPI0_SCLK	I2C0_SDA	FTM_FLT2	LPTMR_ ALT2	FTM0_QD_ PHB	FB_CLKOUT	
37	—	—	—	TSI0_CH11	TSI0_CH11	PTE2		I2C3_SCL			FBa_D0		
38	—	—	—	ADC0_SE16/ TSI0_CH12	ADC0_SE16/ TSI0_CH12	PTE3	SPI0_MOSI	I2C3_SDA			FBa_OE_b		
39	27	25	19	ADC0_SE17/ TSI0_CH13	ADC0_SE17/ TSI0_CH13	PTB2	SPI0_MISO				FBa_CS0_b		
40	28	26	20	ADC0_SE18/ TSI0_CH14	ADC0_SE18/ TSI0_CH14	PTB3	SPI0_MOSI			FBa_CS1_b	FBa_ALE		
41	29	—	—	ADC0_SE19/ TSI0_CH15	ADC0_SE19/ TSI0_CH15	PTE4	UART0_ RTS_b	LPTMR_ ALT3	SPI1_SS		FBa_AD1		
42	30	—	—	ADC0_SE20	ADC0_SE20	PTE5	UART0_ CTS_b	I2C1_SCL	SPI1_SCLK		FBa_AD2		
43	—	—	—	ADC0_SE21	ADC0_SE21	PTE6	UART0_RX	I2C1_SDA	SPI1_MISO		FBa_AD3		
44	31	27	—	ADC0_SE22	ADC0_SE22	PTE7	UART0_TX	PDB0_ EXTRG	SPI1_MOSI	FBa_RW_b	FBa_AD4		
45	32	28	21	BKGD/ MS	Disabled	PTB4	BKGD/ MS						
46	33	29	22	XTAL2	XTAL2	PTB5							
47	34	30	23	EXTAL2	EXTAL2	PTB6							
48	35	31	24	VDD	VDD								
49	36	32	25	VSS	VSS								

64-pin	48-pin	44-pin	32-pin	Default	ALT0	ALT1	ALT2	ALT3	ALT4	ALT5	ALT6	ALT7	EzPort
50	37	33	26	EXTAL1	EXTAL1	PTB7		I2C1_SDA	TMR_CLKIN1				
51	38	34	27	XTAL1	XTAL1	PTC0		I2C1_SCL	TMR_CLKIN0	GPIO0			
52	39	35	28	RESET_b	Disabled	PTC1	RESET_b						
53	—	—	—	CMP0_IN0	CMP0_IN0	PTF0	SPI0_SS				FBa_AD5		
54	—	—	—	Disabled	Disabled	PTF1	SPI0_SCLK			CMP0_OUT	FBa_AD6		
55	—	—	—	CMP0_IN1	CMP0_IN1	PTF2	SPI0_MISO				FBa_AD7		
56	40	36	—	CMP0_IN2	CMP0_IN2	PTF3	SPI0_MOSI			GPIO1	FBa_AD8	I2S0_TXD	
57	41	37	29	CMP0_IN3	CMP0_IN3	PTC2	UART1_RTS_b	SPI1_SS		GPIO2	FBa_AD18	I2S0_TX_FS	
58	42	38	—	Disabled	Disabled	PTF4	UART1_CTS_b	SPI1_SCLK		FBa_D3	FBa_AD19	I2S0_TX_BCLK	
59	43	39	—	Disabled	Disabled	PTF5	UART1_RX	SPI1_MISO		FBa_D2	FBa_RW_b	I2S0_RXD	
60	44	40	—	Disabled	Disabled	PTF6	UART1_TX	SPI1_MOSI		FBa_D1	FBa_AD9	I2S0_RX_FS	
61	45	41	—	Disabled	Disabled	PTF7	UART0_RTS_b		SPI0_SS	FBa_D0	FBa_AD10	I2S0_RX_BCLK	
62	46	42	30	Disabled	Disabled	PTC3	UART0_CTS_b	GPIO3	SPI0_SCLK	CLKOUT	USB_CLKIN	I2S0_MCLK/ I2S0_CLKIN	
63	47	43	31	Disabled	Disabled	PTC4	UART0_RX	GPIO4	SPI0_MISO	PDB0_EXTRG	USB_SOF_PULSE		
64	48	44	32	Disabled	Disabled	PTC5	UART0_TX	GPIO5	SPI0_MOSI	CMT_IRO			

8.2 Pinout diagrams

The following diagrams show pinouts for the 64-pin, 48-pin, 44-pin, and 32-pin packages. These diagrams are representations for ease of reference. See the package drawings for mechanical details.

For each pin, the diagrams show the default function or (when disabled is the default) the ALT1 signal for a GPIO function. However, many signals may be multiplexed onto a single pin.

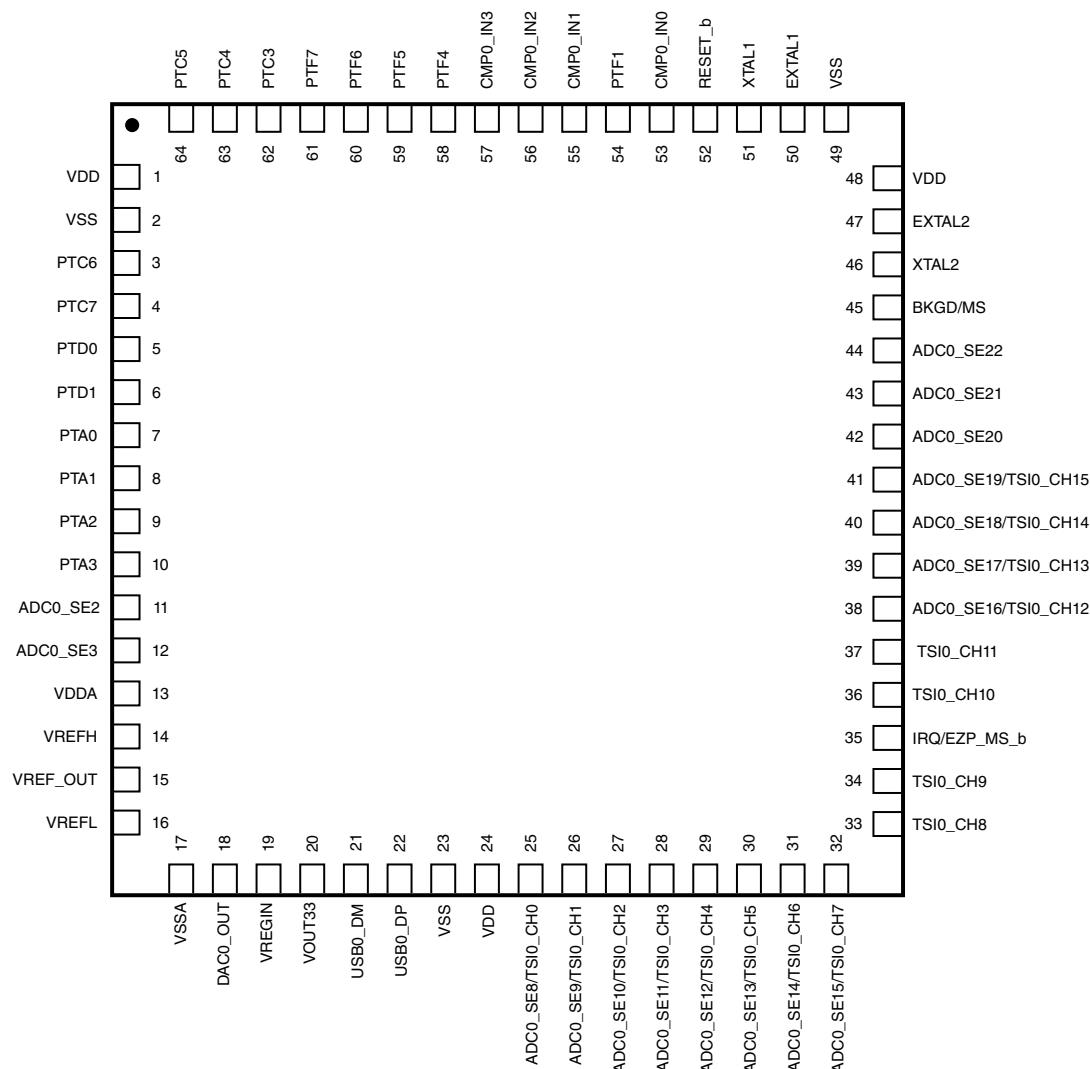


Figure 20. 64-pin LQFP

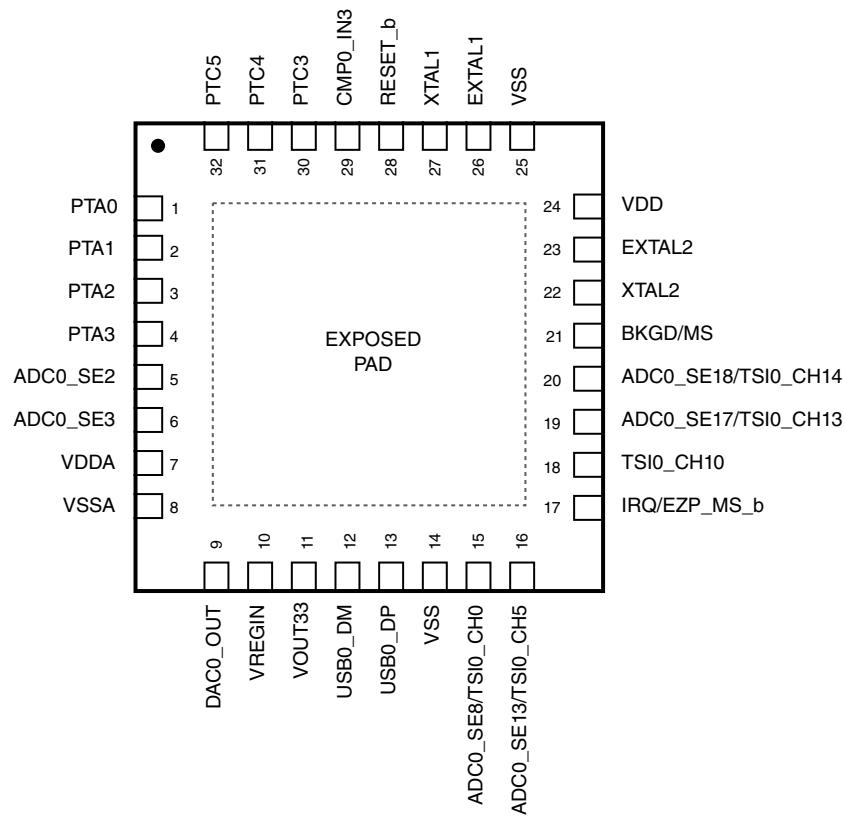


Figure 23. 32-pin QFN

8.3 Module-by-module signals

NOTE

- On PTB0, EZP_MS_b is active only during reset. Refer to the detailed boot description.
- PTC1 is open drain.

Table 38. Module signals by GPIO port and pin

64-pin	48-pin	44-pin	32-pin	Port	Module signal(s)
Power and ground					
1					VDD
24	20	18			VDD

Table continues on the next page...

Table 38. Module signals by GPIO port and pin (continued)

64-pin	48-pin	44-pin	32-pin	Port	Module signal(s)
55				PTF2	CMP0_IN1
56	40	36		PTF3	CMP0_IN2
57	41	37	29	PTC2	CMP0_IN3
54				PTF1	CMP0_OUT
CMT					
64	48	44	32	PTC5	CMT_IRO
I2S0					
5	1			PTD0	I2S0_MCLK/ I2S0_CLKIN
62	46	42	30	PTC3	I2S0_MCLK/ I2S0_CLKIN
6	2			PTD1	I2S0_RX_BCLK
61	45	41		PTF7	I2S0_RX_BCLK
7	3	1	1	PTA0	I2S0_RX_FS
60	44	40		PTF6	I2S0_RX_FS
8	4	2	2	PTA1	I2S0_RXD
59	43	39		PTF5	I2S0_RXD
10	6	4	4	PTA3	I2S0_TX_BCLK
58	42	38		PTF4	I2S0_TX_BCLK
11	7	5	5	PTA4	I2S0_TX_FS
57	41	37	29	PTC2	I2S0_TX_FS
12	8	6	6	PTA5	I2S0_TXD
56	40	36		PTF3	I2S0_TXD
TSI0					
25	21	19	15	PTA6	TSI0_CH0
26				PTD2	TSI0_CH1
27	22	20		PTD3	TSI0_CH2
28				PTD4	TSI0_CH3
29				PTD5	TSI0_CH4
30	23	21	16	PTA7	TSI0_CH5
31	24	22		PTD6	TSI0_CH6
32				PTD7	TSI0_CH7
33				PTE0	TSI0_CH8
34				PTE1	TSI0_CH9
36	26	24	18	PTB1	TSI0_CH10
37				PTE2	TSI0_CH11
38				PTE3	TSI0_CH12
39	27	25	19	PTB2	TSI0_CH13
40	28	26	20	PTB3	TSI0_CH14
41	29			PTE4	TSI0_CH15

Table continues on the next page...

Table 38. Module signals by GPIO port and pin (continued)

64-pin	48-pin	44-pin	32-pin	Port	Module signal(s)
44	31	27		PTE7	SPI1_MOSI
60	44	40		PTF6	SPI1_MOSI
5	1			PTD0	SPI1_SCLK
10	6	4	4	PTA3	SPI1_SCLK
42	30			PTE5	SPI1_SCLK
58	42	38		PTF4	SPI1_SCLK
6	2			PTD1	SPI1_SS
9	5	3	3	PTA2	SPI1_SS
41	29			PTE4	SPI1_SS
57	41	37	29	PTC2	SPI1_SS
UART0					
5	1			PTD0	UART0_CTS_b
32				PTD7	UART0_CTS_b
42	30			PTE5	UART0_CTS_b
62	46	42	30	PTC3	UART0_CTS_b
6	2			PTD1	UART0_RTS_b
33				PTE0	UART0_RTS_b
41	29			PTE4	UART0_RTS_b
61	45	41		PTF7	UART0_RTS_b
4				PTC7	UART0_RX
31	24	22		PTD6	UART0_RX
43				PTE6	UART0_RX
63	47	43	31	PTC4	UART0_RX
3				PTC6	UART0_TX
30	23	21	16	PTA7	UART0_TX
44	31	27		PTE7	UART0_TX
64	48	44	32	PTC5	UART0_TX
UART1					
11	7	5	5	PTA4	UART1_CTS_b
58	42	38		PTF4	UART1_CTS_b
12	8	6	6	PTA5	UART1_RTS_b
57	41	37	29	PTC2	UART1_RTS_b
10	6	4	4	PTA3	UART1_RX
59	43	39		PTF5	UART1_RX
9	5	3	3	PTA2	UART1_TX
60	44	40		PTF6	UART1_TX